



IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Applicant : Henry A. Hill
Serial No. : 10/616,504
Filed : July 8, 2003
Title : CYCLIC ERROR COMPENSATION IN INTERFEROMETRY SYSTEMS

Art Unit : 2877
Examiner :

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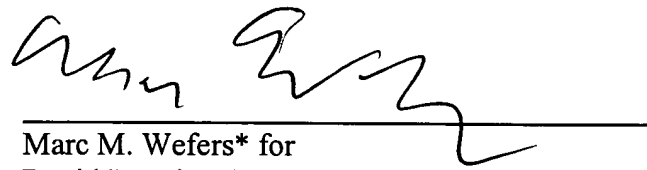
INFORMATION DISCLOSURE STATEMENT

Please consider the references listed on the attached form PTO-1449. Copies of non-patent references are enclosed.

This statement is being filed within three months of the filing date of the application or before the receipt of a first Office Action on the merits. Please apply any charges or credits to Deposit Account No. 06-1050.

Respectfully submitted,

Date: 10/28/04



Marc M. Wefers* for
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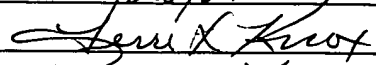
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*See attached document certifying that Marc M. Wefers has limited recognition to practice before the U.S. Patent and Trademark Office under 37 C.F.R. § 10.9(b).

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I hereby certify under 37 CFR §1.8(a) that this correspondence is being deposited with the United States Postal Service as first class mail with sufficient postage on the date indicated below and is addressed to the Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450.

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Substitute Form PTO-1449

U.S. Department of Commerce
Patent and Trademark Office

Attorney's Docket No.

09712-330001

Application No.

10/616,504

**Information Disclosure Statement
by Applicant**

(Use several sheets if necessary)

Applicant

Henry A. Hill

Filing Date

July 8, 2003

Group Art Unit

2877

U.S. Patent Documents

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	AA	4,413,908	11/1983	Abrams et al.			
	AB	4,948,254	08/1990	Ishida			
	AC	5,151,749	09/29/1992	Tanimoto et al.			
	AD	5,249,016	9/1993	Tanaka, Hiroshi			
	AE	5,331,400	07/1994	Wilkening et al.			
	AF	5,404,222	04/1995	Lis			
	AG	5,432,603	07/1995	Sentoku et al.			
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	AK	5,724,136	03/03/1998	Zanoni			
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	AW	6,160,619	12/2000	Magome			
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	AZ	6,271,923	08/07/2001	Hill			
	AAA	6,304,318	10/16/2001	Matsumoto			

Examiner Signature

Date Considered

EXAMINER: Initials citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

Substitute Form PTO-1449 (Modified) Information Disclosure Statement by Applicant (Use several sheets if necessary) (37 CFR §1.98(b))	U.S. Department of Commerce Patent and Trademark Office	Attorney's Docket No. 09712-330001	Application No. 10/616,504
	Applicant Henry A. Hill		
	Filing Date July 8, 2003	Group Art Unit 2877	

U.S. Patent Documents

Examiner Initial	Desig. ID	Document Number	Publication Date	Patentee	Class	Subclass	Filing Date If Appropriate
	ABB	6,313,918	11/06/2001	Hill et al.			
	ACC	6,687,013	02/2004	Isshiki et al.			
	ADD	6,747,744	06/08/2004	Hill			
	AEE	6,806,961	10/19/2004	Hill			
	AFF	2002/0048026 A1	04/25/2002	Isshiki et al.			

Foreign Patent Documents or Published Foreign Patent Applications

Examiner Initial	Desig. ID	Document Number	Publication Date	Country or Patent Office	Class	Subclass	Translation	
							Yes	No
	AGG	JP 7-351078	12/1995	Japan (Abstract Only)				
	AHH	JP 8-117083	04/1996	Japan (Abstract Only)				
	AII	JP 10-260009	09/29/1998	Japan (with Abstract)				X
	AJJ							

Other Documents (include Author, Title, Date, and Place of Publication)

Examiner Initial	Desig. ID	Document
	AKK	Badami V.G. et al., "Investigation of Nonlinearity in High Accuracy Heterodyne Laser Interferometry," 1997 PROCEEDINGS, Vol. 16, pp. 153-156.
	ALL	Bennett, S.J. <u>Optics Communications</u> , 4:6, pp. 428-430, 1972
	AMM	Bobroff, N., "Recent Advances in Displacement Measuring Interferometry," MEASUREMENT SCIENCE & TECHNOLOGY, Vol. 4, No. 9, September 1993, pp. 907-926.
	ANN	Hines, B. et al., "Sub-Nanometer Laser Metrology - Some Techniques and Models," JET PROPULSION LABORATORY, CALIFORNIA INSTITUTE OF TECHNOLOGY, pp. 1195-1204.
	AOO	Oka K. et al., "Polarization Heterodyne Interferometry Using Another Local Oscillator Beam," OPTICS COMMUNICATIONS, 92 (1992), 1-5.
	APP	Wu, C.M. et al., "Analytical Modeling of the Periodic Nonlinearity in Heterodyne Interferometry," APPLIED OPTICS, Vol. 37, No. 28, 1 October 1998, pp. 6696-6700.
	AQQ	

Examiner Signature	Date Considered
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